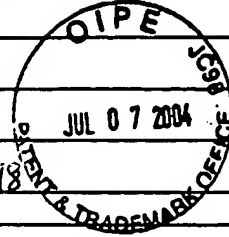


## INFORMATION DISCLOSURE CITATION

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Examiner Initial*	Document Number	Issue Date	Name	Class	Sub Class	Filing Date If Appropriate
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## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

dh	C. Duvvury and A. Amerasekera, "ESD: A pervasive reliability concern for IC technologies," <i>Proc. of IEEE</i> , vol. 81, pp. 690-702, May 1993.
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Examiner	<i>Neat</i>	Date Considered	10/16/2005
*Examiner:	Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.		
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